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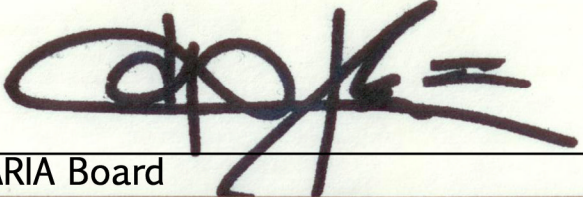
Best Paper Award

Low-Code Solution for IoT Testing

By

Hugo Cunha, João Pascoal Faria, Bruno Lima

Presented during VALID 2019, The Eleventh International Conference on Advances in System Testing and Validation Lifecycle, held in Valencia, Spain during November 24 - 28, 2019.


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